

X-ray CT investigation of defect on niobium coated copper RF cavity

S. Aliasghari^{1,2,*}, P. Skeldon², A. Gholinia², R. Valizadeh¹

¹ASTeC, STFC Daresbury Laboratory, Daresbury, Warrington, UK. ²Corrosion and Protection Group, School of Materials, The University of Manchester, UK.

*sepideh.aliasghari@stfc.ac.uk

Superconducting radio frequency cavity (SRF)













- Applies to virtually any sample
- Multiscale
- Non-destructive

X-ray CT

As you can X-ray CT involves 3 steps

1) the acquisition of x-ray images, also called radiographs or projections whilst the sample rotates through 360 degrees

2) The projections need to be reconstructed to construct a 3D image which is a virtual replica of the object scanned

3) The 3D image still needs to be visualised and importantly measurements taken and analysis made using special software.

Important point are that it provides a 3D image and can be applied to virtually any object (although it is difficult to look at very dense objects such as those made from lead) we can use it at different length scales and because it is non destructive we can look at changes to samples over time.



The University of Manchester

Sample preparation





X-ray CT instrument





Acquisition Settings

Instrument: Zeiss Xradia Versa 520 XRM Filter: LE5 Energy: 140 keV Current: 71 µA Exposure time: 20 s Sample size: 4 mm * 2 mm Number of projections: 2001 Voxel size: 1.89 µm



A volume rendering of the Nb-coated Cu sample.





A volume rendering of the Nb-coated Cu sample with the location of the virtual cross section shown (left) and the virtual cross section showing the defect (right).



A volume rendering of the Nb-coated Cu sample with the location of the virtual cross section shown (top) and the virtual cross section (bottom).



A volume rendering of the Nb-coated Cu sample with the location of the virtual cross section shown (top) and the virtual cross section (bottom).



A volume rendering of the Nb-coated Cu sample with the location of the virtual cross section shown (top) and the virtual cross section (bottom).





Surface of Nb





Interface





Virtual cross-section showing the coating and substrate. The interface is highlighted in cyan and the defects at the coating surface is highlighted in red.



3D view of the interface coloured using the ycoordinate of the interface. The defects on the coating surface is rendered in red.



FIB on cross section Where is origin the crack

 HV
 curr
 WD
 tilt
 HFW
 mag ⊞

 20.00 kV
 2.4 nA
 4.9 mm
 52 °
 51.2 μm
 2 500 x

10 µm -

- a) Film deposition
- b) interface
- c) Bulk substrate



FIB on cross section



Defect



820	HFW	WD	HV	tilt	mag 🎛	curr	⊷−−−− 5 µm −−−−−•
	19.9 µm	10.1 mm	5.00 kV	54 °	7 500 x	3.41 nA	

Defect



Defect



Crack propagation



Crack propagation



EDS analysis on defect



EDS analysis on Cu substrate



Element	Atomic %
Cu	96.06
Ga	1.30
Nb	1.16
Os	1.48
Total:	100.00

EDS analysis on Nb coating



Element	Atomic %
Cu	23.73
Ga	5.57
Zr	2.04
Nb	68.66
Total:	100.00

EDS analysis on interface



Element	Atomic %
Cu	65.79
Ga	13.20
Nb	21.02
Total:	100.00

Hypothesis

- 1- Impurity like Os from Cu during extraction can trap H then NbH2 forms
- 2- Impurity of a sputtering or carrier gas
- 3- forming of micro cell Nb cathode, Cu anode then residual hydrogen evolution in grain boundary of Nb, despite the efforts to eliminate the hydrogen sources and the use of nonevaporable getters, hydrogen reduction was unfortunately not effective
- 4-Inter-grain defects can be also generated by impurities trapped in the film and surface roughness and in turn may cause intrinsic defects



Acknowledgment

* * * * * * *

 This project has received funding from the European Union's Horizon 2020 research and innovation programme under the Marie Skłodowska-Curie grant agreement (GA) No. 665593 awarded to the Science and Technology Facilities Council.





The University of Manchester



Thanks

